## **TEM Basic Class**

Technical training classes to take after passing all tests of beginner class.

There are three basic classes and you must take at least one: Multiple selectable.

After completing all classes taken in JEM-2100F

B license for JEM-2100F will be issued, and you are available for Common use.

Those who wish to use only the JEM-2100 will be required to take a basic class with JEM-2100, then you will obtain a license

Those who wish to use only the JEM-ARM200F must have a JEM-2100F license or have experience equivalent to the JEM-2100F license.

I'd like to see

nanoparticles, and to know

the size distribution.

I'd like to see the defects in the crystal grain boundary, and to analyze the composition of the precipitates.

I'd like to analyze coreshell structured nanoparticles with element mapping.



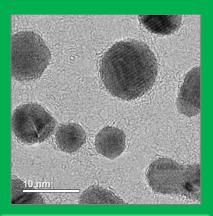
Selectable



Selectable

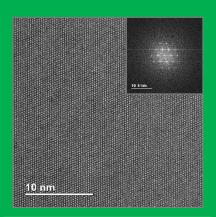


## Nano Particle



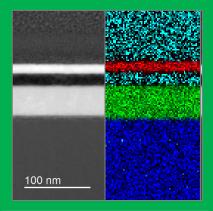
- I. Technical Support
- 2. Standard sample or your own sample can be used
- TEM alignment (review), Checking the visibility of NPs with differences in each Micro-grids to find out appropriate one, Setting conditions for HRTEM, etc.

## **HRTEM**



- I. Technical Support
- Standard sample: Your own sample cannot be used
- TEM Alignment (review), Adjustment of the crystal orientation, SAED (review), Setting conditions for HRTEM, etc.

## STEM-EDS



- 1. Technical Support
- Standard sample: Your own sample cannot be used
- 3. STEM basic alignment, STEM-EDS, etc.



**↓ ∱** Fai



Technical skills test



B-License Issuance of JEM-2100F/JEM-2100 or Optional class